

Search Notes

Application/Control No.

10/644,407

Examiner

KEVIN L. LEE

Applicant(s)/Patent under
Reexamination

BAAN, JACOB DE

Art Unit

3753

SEARCHED

Class	Subclass	Date	Examiner
137	615	9/26/2005	KL
141	387 388		
441	4 5		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search- see search history printout	9/26/2005	KL